

Semiconductor Characterization System

Manufacturer: [Keithley](#)

Model: [Keithley 4200-SCS Parameter Analyzer](#)

Description:

The 4200-SCS is a modular, fully integrated parameter analyzer that performs electrical characterization of materials, semiconductor devices and processes. From basic I-V and C-V measurement sweeps to advanced ultra-fast pulsed I-V, waveform capture, and transient I-V measurements, the 4200-SCS provides the researcher or engineer with critical parameters needed for design, development or production.

